

**Search Notes**

Application/Control No.

10/679,789

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

SCOONES ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	270		
	271		
	273		
	274		
	275		
	277		
	280		
	281	3/05	gA

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner